

Reliability in a Gaussian Environment

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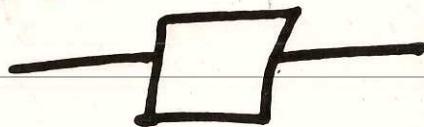
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THE HAZARD RATE

- DEF'N.

$$h(t) = P_a [t < \tau \leq t+dt \mid \tau > t] \cancel{\frac{d}{dt}}$$

$$= \frac{f(t)}{1-F(t)}$$



$$\therefore F(t) = 1 - e^{-\int_0^t h(t') dt'}$$

- RELIABILITY = $P_a \{ \tau > t \}$

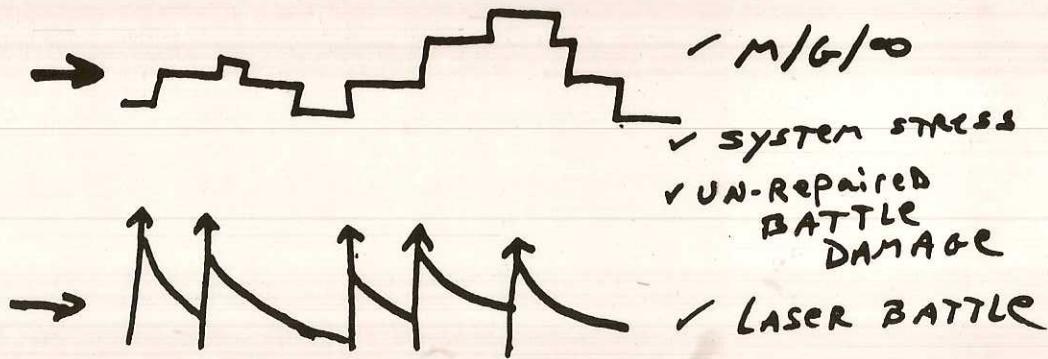
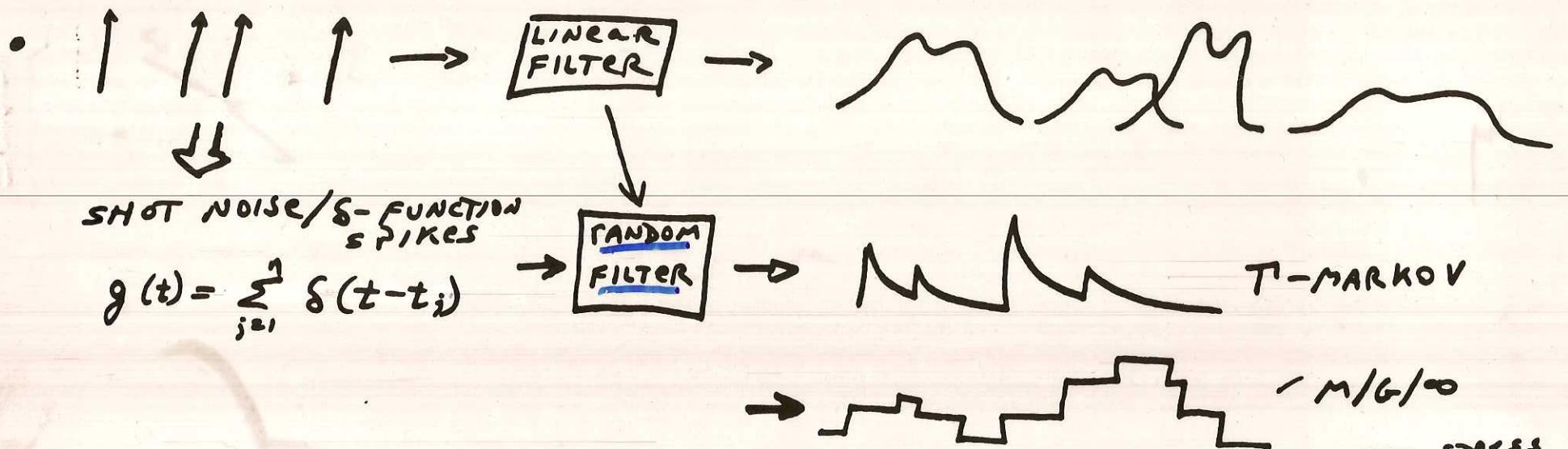
$$R(t) = 1 - F(t) = e^{-\int_0^t h(t') dt'}$$

$$\rightarrow h(t) = -\frac{d}{dt} \ln R(t)$$

- Presumably averaged over

- MFG VARIABLES
- How it's operated
- environmental cond's
- ⋮

FILTERED SHOT NOISE PROCESSES



- $h(t') = \lambda(t') + \sum_{j=1}^{\infty} r_j(t'-t_j)$

\sum random response function

e.g. if failures \propto unrepairs battle damage

$$r_j(t'-t_j) = K \beta_j \{ \Theta(t'-t_j) - \Theta(t-t_j - \tau_j) \} \sim \frac{\beta_j}{\tau_j}$$

- ALL \Rightarrow non-exp'l lifetimes

GENERAL STOCHASTIC HAZARD PROCESS

- For j -th comp. $h_j(t) = \lambda_j(t) + g_j(t)$
 - $\lambda_j(t)$ stochastic part
 - $g_j(t)$ wearout/env. factors
indep. V comp's.

- Conditioned on realization of $h(t)$

$$R_h(t) = e^{-\int_0^t h(t') dt'}$$

- FOR 1-comp. \rightarrow simply ave. over sample paths

$$R(t) = E_h [R_h(t)] = E \left\{ e^{-\int_0^t h(t') dt'} \right\}$$

- Define effective hazard rate

$$\hat{h}(t) = -\frac{d}{dt} \ln R(t) \quad (\neq E\{h(t)\})$$

- e.g. 2-comp's in // :



$$R_h(t) = 1 - (1 - R_{h_1}(t))(1 - R_{h_2}(t)) = R_{h_1}(t) + R_{h_2}(t) - R_{h_1} \cdot R_{h_2}$$

$$\therefore R(t) = R_1 + R_2 - E \left\{ e^{-\int_0^t (h_1 + h_2)(t') dt'} \right\} \neq R_1 + R_2 - R_1 \cdot R_2$$

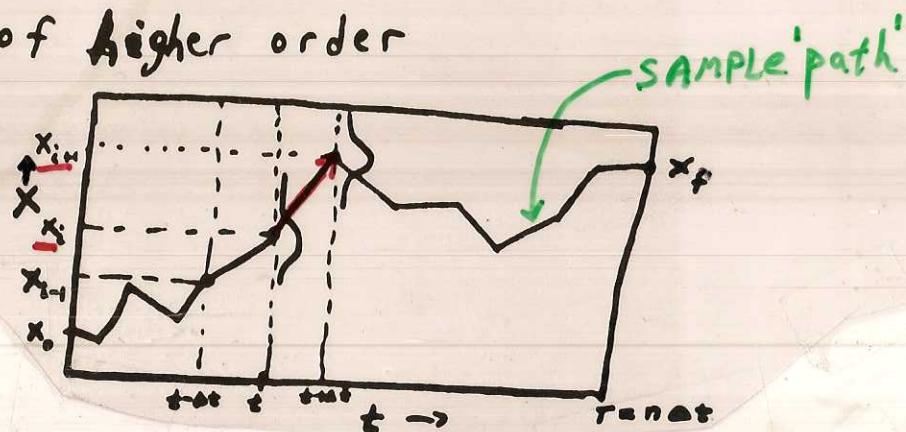
SHORT-TIME LIMIT OF SOLUTION: SDE

- $$\hat{P}_{\text{rd}}[x_i + \Delta x, t + \Delta t / x_i, t] = \frac{[1 + \hat{\varphi} g(x_i) \Delta t]}{\sqrt{2\pi \sigma^2 \Delta t}} \exp\left\{-\frac{(\Delta x + g(x_i) \Delta t)^2}{2 \sigma^2 \Delta t}\right\}$$
 - pdf of \tilde{x}_{i+1}

- Dropped terms in Δt of higher order

- $0 \leq \hat{\varphi} < 1$

- Probability of a 'path'



- really a prob. density functn.

- in limit as $\Delta t \rightarrow 0 \Rightarrow$ prob. density functional of a path

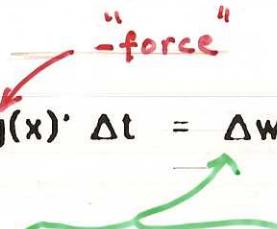
- $= \prod_i \hat{P}_{\text{rd}}[\underbrace{x_i + \Delta x, t_i + \Delta t}_X / x_i, t_i]$
 - USED MARKOV Property
 - CONDITIONAL ON x_0

continuous

A Transformation on Path Integrals

$$\Delta y + 'f(y)'\Delta t = \sqrt{g(y)}\Delta w \quad \begin{matrix} \text{Stochastic Differential} \\ \text{Equation (SDE)} \end{matrix}$$

↑ Environment ↑ Wiener process

- Multiplicative noise term of form $\sqrt{g(x)}\Delta w$ can be transformed with appropriate stochastic calculus.
- stochastic differential equation: $\Delta x + 'g(x)'\Delta t = \Delta w$

- \exists ambiguity wrt ' $g(x)$ ' even though considering additive noise term
- $\Delta x = x_{i+1} - x_i$; $\Delta w = w_{i+1} - w_i$; w = Wiener process
- Possible "discretizations": ' $g(x)$ ' = $(1 - \hat{\alpha}) g(x_i) + \hat{\alpha} g(x_{i+1})$
- $\hat{\alpha} = 1/2 \Rightarrow$ Stratonovich SDE; $\hat{\alpha} = 0 \Rightarrow$ Ito SDE
- since $\sigma(x) = \text{const.}$ (possibly after a transformation)
Fokker-Planck eq'n is same (but may be relevant for path integral)

Short-Time Propagator for Paths

- require short time conditional pdf for Chapman-Kolmogorov eq./path integral limit --> GAUSSIAN for $\Delta t \rightarrow 0$

- Expand SDE in Taylor series about x_1 :

$$\Delta x + [g(x_1) + \hat{\alpha} g'(x_1) \Delta x + o(\Delta x)] \Delta t = \Delta w$$

$$\Delta x [1 + \hat{\alpha} g'(x_1) \Delta t] + g(x_1) \Delta t = \Delta w$$

$$\Rightarrow \Delta x = -g(x_1) \Delta t / [1 + \hat{\alpha} g'(x_1) \Delta t] + \Delta w / [1 + \hat{\alpha} g'(x_1) \Delta t]$$

- Hence, conditional on x_1 , for short times, x_{1+1} will have

mean $E(x_{1+1}) \approx x_1 + g(x_1) \Delta t / [1 + \hat{\alpha} g'(x_1) \Delta t]$

- and Var(x_{1+1}) $\approx \sigma^2 \Delta t / [1 + \hat{\alpha} g'(x_1) \Delta t]^2$

THE TRANSFORMATION FORMULA

- Express Expectations of Functionals - over sample paths of SDE
 - IN TERMS OF EXPECTATIONS OVER SAMPLE PATHS OF WIENER (Brownian motion) PROCESS

$$\underset{\text{SDE}}{E_{x_0, x_f}} \left\{ F[x(\cdot)] \right\} = E_{x_0, x_f} \left\{ F[x(\cdot)] e^{\hat{\alpha} \int_0^t g'(w) dt - \int_0^t \frac{g(x) dx}{\sigma^2} - \int_0^t \frac{g^2(x) dt}{2\sigma^2}} \right\}$$

- choose $\hat{\alpha} = \frac{1}{2}$ for convenience \rightarrow Stratonovich (ordinary) calculus
(NOT really necessary)

- Let $G'(x) \equiv g(x)$

$$\boxed{E_{x_0, x_f} \underset{\text{SDE}}{\left\{ F[x(\cdot)] \right\}} = e^{\frac{G(x_0) - G(x_f)}{\sigma^2}} E \left\{ F[x(\cdot)] e^{\int_0^t dt [g'(x) - \frac{g^2}{2\sigma^2}]} \right\}}$$

APPLICATIONS OF THE TRANSFORMATION

Let $F[x_0] = 1$, $g(x) = \lambda x$ (ORNSTEIN-UHLENBECK PROCESS)

$$LHS = \hat{P}_{rd}[x_{t+1} | x_0, 0] = \frac{\lambda}{\pi \sigma^2 (1 - e^{-2\lambda t})} \exp \left\{ \frac{-\lambda (x_t - x_0 e^{-\lambda t})^2}{\sigma^2 (1 - e^{-2\lambda t})} \right\}$$

$$RHS = e^{\frac{x_0^2 - x_t^2}{2\sigma^2} + \frac{4t}{\lambda}} * E \left\{ e^{-\frac{4t}{\lambda} \cdot \int_0^t x^2(w) dt} \right\}_w$$

\Rightarrow a little algebra + translate into cosh & sinh

Gives a now classic formula of Cameron/Martin
(KAC FUNCTIONAL)

Now, identify hazard rate function as $\propto X^2(t)$, $X \sim$ Wiener Process, w

$$\therefore R(t) = \int_0^t E \left\{ e^{-\lambda \int_0^t X^2(w) dt} \right\}_w = E \left\{ e^{-\int_0^t \lambda(t) dt} \right\}$$

APPLICATIONS TO ORNSTEIN-UHLENBECK PROCESS

- $h(t) = \alpha X^2(t)$, $X \sim \text{O.U. Process}$

$$E_{x_0, x_f} \left\{ e^{-\int_0^t x^2(u) du} \right\}_{\text{O.U.}} = e^{x_0^2 - x_f^2 + \frac{\lambda}{2} t} E_{x_0, x_f} \left\{ e^{-\left[\frac{\lambda}{2} t + \alpha \right] \int_0^t x^2(u) du} \right\}_w$$

- $E\{\cdot\}$ on RHS is now same as above

- set $x_0 = 0$ & $\int dx_f$ to obtain $R(t)$

- OFFSET O.U. : Constant Force/Voltage $L \frac{di}{dt} + Ri = f(t) + V_0$
i.e. $\Delta x + \lambda(x - \bar{x})\Delta t = \Delta \omega$

✓ use $\hat{x} = \pm \sqrt{\text{Var(O.U.)}}$ to see effect of \hat{x} in SIMULATION

AVERAGES OVER PATHS

- CALCULATE Expected values of function $F[\{x_i\}] = F[x_0, x_1, x_2, \dots, x_n]$

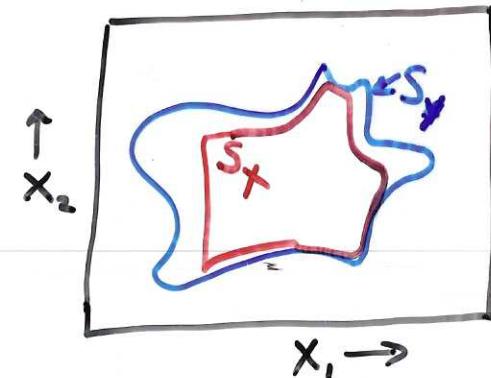
$$E\{F(\{x_i\})\} = \int dx_1 \dots \int dx_{n-1} \underbrace{\prod_i}_{\text{P}_r} \hat{P}_{rd}[x_{i+1}, t_{i+1} | x_i, t_i] F(\{x_i\}_{i=0}^n)$$

- TAKE THE LIMIT \rightarrow continuous paths: $x_0 \rightarrow x_f$
 - insert our short-time pdf
 - $F[\cdot] \rightarrow$ functional of paths

$$\xrightarrow[n \rightarrow \infty]{\Delta t \rightarrow 0} \underbrace{\int \mathcal{D}x(t) F[x(t)] \exp \left\{ -\frac{1}{2} \int_0^t \frac{\dot{x}^2}{2\sigma^2} dt - \int_0^t \frac{\dot{x}(x)}{\sigma^2} dx - \frac{1}{2} \int_0^t \frac{dx^2}{\sigma^2} dt \right\}}_{\substack{\lim_{\Delta t \rightarrow 0} \prod_i \frac{dx_i}{\sqrt{2\pi\sigma^2\Delta t}} \\ \text{usual Wiener measure}}}$$

ANALOGUE OF OUR PROCEDURE

- $\vec{y} \sim \text{pdf } g_{\vec{Y}}(\vec{y})$: Support S_y
 $\vec{x} \sim \text{pdf } f_{\vec{X}}(\vec{x})$: Support S_x $S_x \subseteq S_y$



- $E_{\vec{x}} \left\{ \hat{F}(\vec{x}) \right\} = \int_{S_x} \hat{F}(\vec{x}) f(\vec{x}) d^k x$
 $= \int_{S_x} \hat{F}(\vec{x}) \frac{f_x(\vec{x})}{g_y(\vec{x})} \cdot g_y(\vec{x}) d^k x$
 $= E_{\vec{y}} \left\{ \hat{F}(\vec{y}) \frac{f_x(\vec{y})}{g_y(\vec{y})} \cdot 1_{[\vec{y} \in S_x]} \right\}$ (1)

- If $S_x = S_y$, \Rightarrow
 $= E_{\vec{y}} \left\{ \hat{F}(\vec{y}) \frac{f_x(\vec{y})}{g_y(\vec{y})} \right\}$ (2)

→ Don't need to calculate JACOBIAN if $g_y(\vec{y})$ known, Eq.(2) helpful.

• If $\vec{x} \leftrightarrow \vec{y}$ (1-1), using Eq.(1) may be helpful.
 (because $S_x \neq S_y$)

THE (WIENER PROCESS)²

- $h(t) = \lambda(t) + \alpha \underline{X^2(t)}$ where $X(t) \sim \text{Wiener Process}$

• Require:

$$C_{X^2}[-i\gamma(0)] = E\left\{ e^{\alpha \int_0^t \gamma(s) X^2(s) ds}\right\}$$

- CAMERON & MARTIN (BULL. AM. MATH. SOC. 1945)
TRANS " " " 1949)

— EVALUATED USING LINEAR TRANSFORMATIONS OF SPACE OF SAMPLE PATHS, $X(t)$, ONTO ITSELF
-- related to sol'n of certain STURM-LIOUVILLE D.E.'s

$$f''(t) + \alpha \gamma(t) f(t) = 0 \quad \exists f_1(0) = f'(0) = 0$$

$$\Rightarrow C_{X^2}[-i\gamma(0)] = \left[\frac{f_\alpha^{(t)}}{f_\alpha^{(0)}} \right]^{\frac{1}{2}} \quad \begin{aligned} &\text{where } -\infty < \alpha < \alpha_0 \\ &\text{✓ } f_\alpha(\cdot) \text{ depends on } \gamma(0) \end{aligned}$$

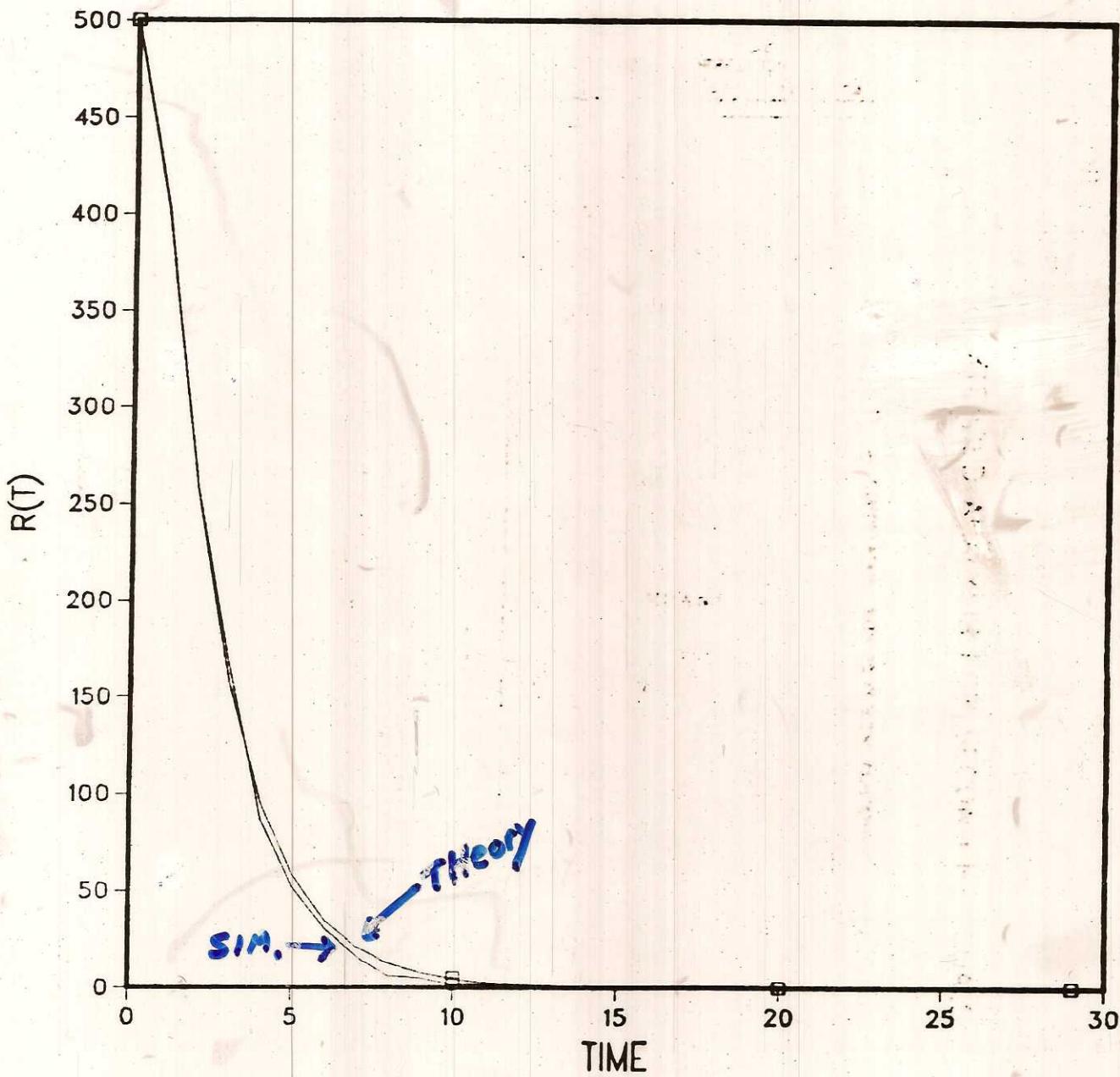
- For $\gamma = -1$ C & M showed

$$C_{X^2}[i] = \left[\frac{1}{\cosh(\sqrt{\alpha} t)} \right]^{\frac{1}{2}}$$

$$\boxed{R(t) = e^{-m\alpha t} \frac{1}{\sqrt{\cosh(\sqrt{m\alpha} t)}}}$$

For m-comp's in series

RELIABILITY
 (WIENER PROCESS)²



$$h(t) = \alpha x^2$$

$$x \leftarrow x + \sqrt{2D \cdot dt} * N$$

IF ($U \leq \alpha x^2 dt$) \Rightarrow FAIL

$$dt = .01$$

$$\sigma^2 = 2D = \frac{1}{2}$$

$$\alpha = 1.$$

STATIONARY-GAUSSIAN ENVIRONMENT

• ORNSTEIN-UHLENBECK PROCESS

$$-\dot{x} + \lambda x = \gamma(t)$$

e.g. $L \frac{dx}{dt} + Rx = V(t)$

$$P(x, t | x_0, t_0) = \left[\frac{\lambda}{\pi \sigma^2 (1 - e^{-2\lambda t})} \right]^{\frac{1}{2}} \exp \left\{ -\frac{\lambda}{\sigma^2} \frac{(x - x_0 e^{-\lambda t})^2}{(1 - e^{-2\lambda t})} \right\}$$

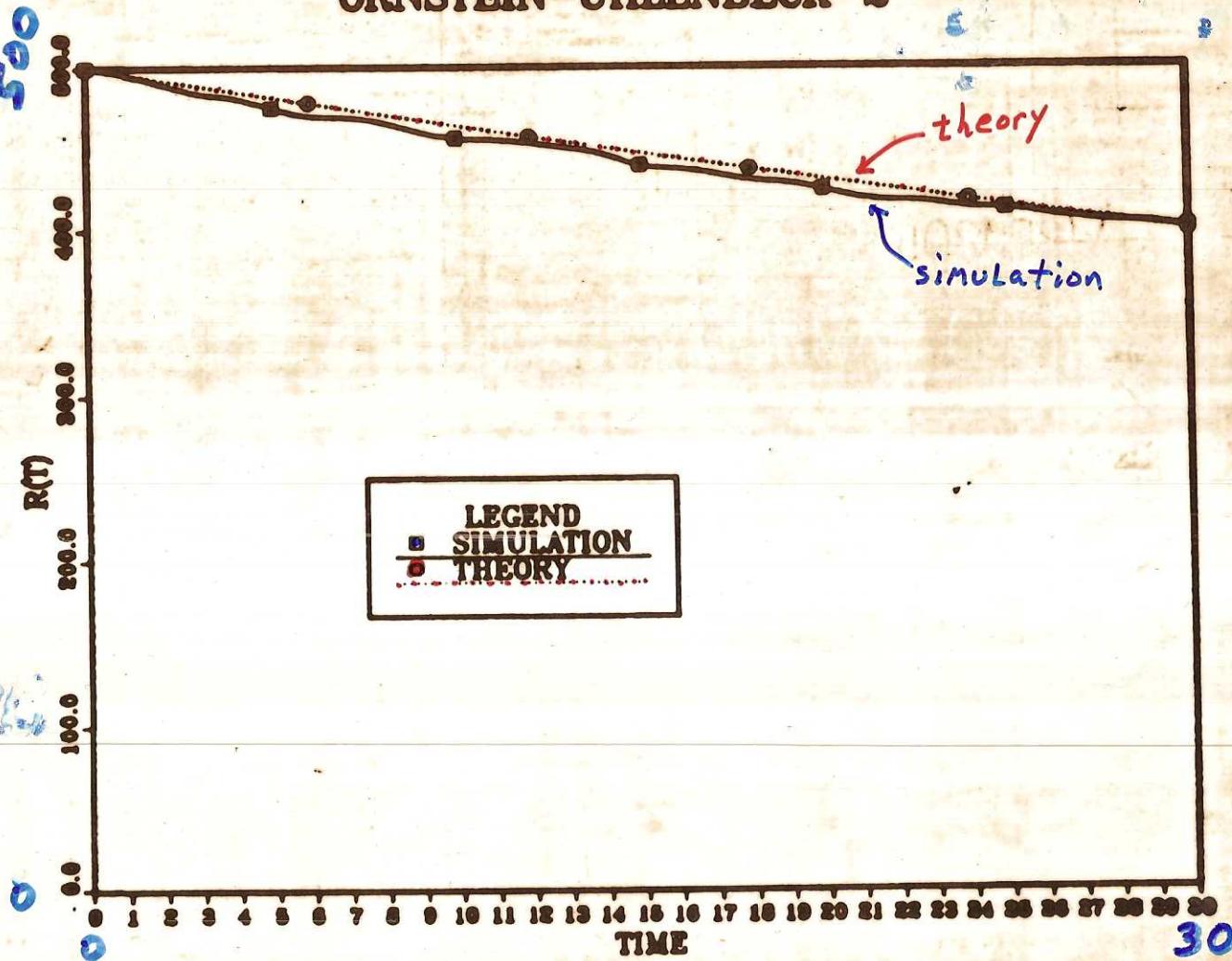
Hazard rate, $h(t) = \alpha x(t)$

$$R(t) = E \left\{ e^{-\alpha \int_{x_0=0}^t x^2 dt} \right\}$$

$$R(t) = \frac{e^{\frac{\lambda}{2}t} (\lambda^2 + 2\sigma^2 \alpha)^{1/4}}{\left[\lambda \sinh(\sqrt{\lambda^2 + 2\sigma^2 \alpha} t) + \sqrt{\lambda^2 + 2\sigma^2 \alpha} \cosh(\sqrt{\lambda^2 + 2\sigma^2 \alpha} t) \right]^{1/2}}$$

ORNSTEIN-UHLENBECK²

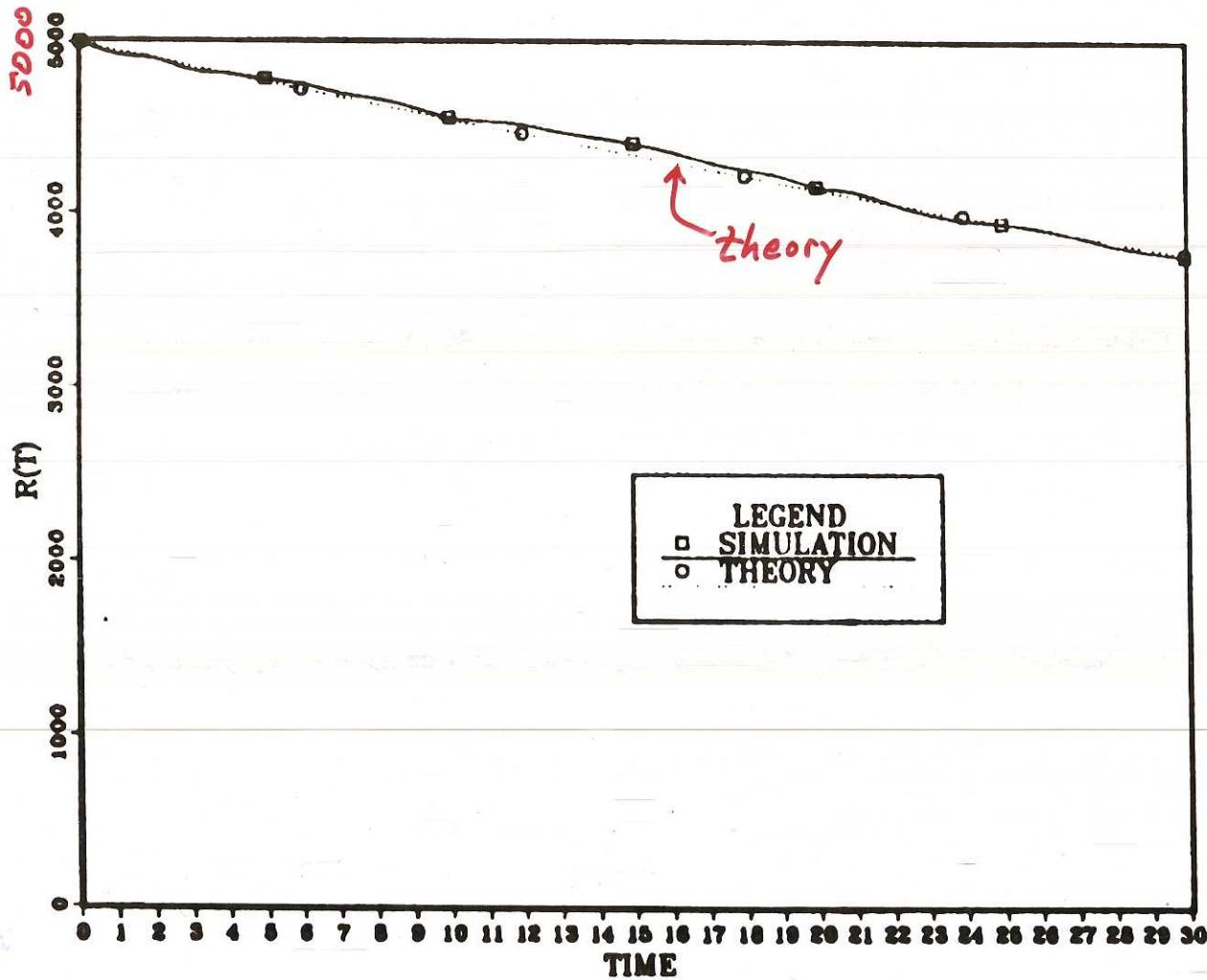
• 462.



$$x \leftarrow x e^{-\Lambda dt} + \sqrt{2 \cdot \sigma^2 \cdot dt} N$$

$$\begin{aligned} dt &= .003 \\ \sigma^2 &= \frac{1}{2} = 2.0 \\ \Lambda &= 33.3 \end{aligned}$$

OFFSET ORNSTEIN-UHLENBECK**2



$$\Delta X + \lambda (x - \hat{x}) \Delta t = \Delta w$$

$$\hat{x} = \frac{1}{2} \sqrt{\text{Var(O.U.)}}$$